SCLS169B - DECEMBER 1982 - REVISED MAY 1997

- Inputs Are TTL-Voltage Compatible
- Package Options Include Plastic Small-Outline (D), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

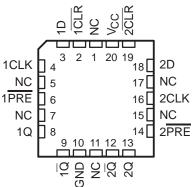
description

The 'HCT74 contain two independent D-type positive-edge-triggered flip-flops. A low level at the preset (PRE) or clear (CLR) inputs sets or resets the outputs regardless of the levels of the other inputs. When PRE and CLR are inactive (high), data at the data (D) input meeting the setup time requirements are transferred to the outputs on the positive-going edge of the clock (CLK) pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of CLK. Following the hold-time interval, data at the D input may be changed without affecting the levels at the outputs.

The SN54HCT74 is characterized for operation over the full military temperature range of -55° C to 125°C. The SN74HCT74 is characterized for operation from -40° C to 85° C.

SN54HCT74 J OR W PACKAGE SN74HCT74 D, N, OR PW PACKAGE (TOP VIEW)								
1CLR [1	14	V _{CC}					
1D [2	13	2CLR					
1CLK [3	12	2D					
1PRE [4	11	2CLK					
1Q [5	10	2PRE					
1Q [6	9	2Q					
GND [7	8	2Q					

SN54HCT74 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

	T UNCTION TABLE							
	INP	UTS		OUT	PUT			
PRE	CLR	CLK	D	Q	Q			
L	Н	Х	Х	Н	L			
н	L	Х	Х	L	Н			
L	L	Х	Х	н†	H‡			
н	Н	↑	Н	н	L			
н	Н	↑	L	L	Н			
н	Н	L	Х	Q ₀	Q ₀			

FUNCTION TABLE

[†] This configuration is unstable; that is, it does not persist when PRE or CLR returns to its inactive (high) level.



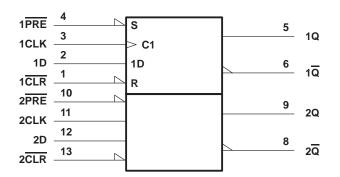
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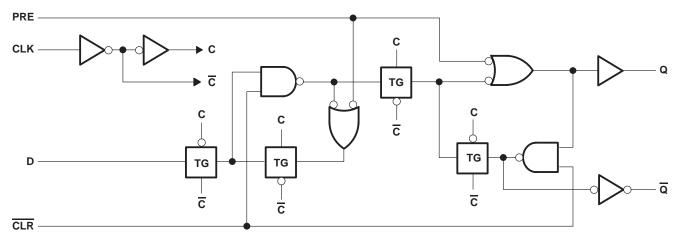
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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, PW, and W packages.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range[‡]

Supply voltage range, V _{CC} Input clamp current, I _{IK} (V _I < 0 or V _I > V _{CC}) (see	ee Note 1)	±20 mA
Output clamp current, I_{OK} (V _O < 0 or V _O > V _{CO}	_C) (see Note 1)	±20 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$		±25 mA
Continuous current through V _{CC} or GND		
Package thermal impedance, θ_{JA} (see Note 2):	: D package	127°C/W
	N package	
	PW package	170°C/W
Storage temperature range, T _{stg}		65°C to 150°C

Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



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recommended operating conditions

			SN	154HCT7	'4	SN74HCT74		UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	V _{CC} = 4.5 V to 5.5 V	2	11	5.	2			V
VIL	Low-level input voltage	V _{CC} = 4.5 V to 5.5 V	0	A.F.	0.8	0		0.8	V
VI	Input voltage		0	7	VCC	0		VCC	V
Vo	Output voltage		0	22	VCC	0		VCC	V
tt	Input transition (rise and fall) time		00	3	500	0		500	ns
Τ _Α	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		Vee	T _A = 25°C			SN54HCT74		SN74HCT74		UNIT
PARAMETER	TEST CO	NDITION5	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
Vou	$\lambda = \lambda = 0$	I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		V
Voh	$V_{I} = V_{IH} \text{ or } V_{IL}$	I _{OH} = -4 mA	4.5 V	3.98	4.3		3.7	h	3.84		V
Ve	$\lambda = \lambda + \sigma \lambda$	I _{OL} = 20 μA	4.5 V		0.001	0.1		0.1		0.1	V
VOL	$V_{I} = V_{IH} \text{ or } V_{IL}$	I _{OL} = 4 mA	4.3 V		0.17	0.26		0.4		0.33	v
li li	VI = VCC or 0		5.5 V		±0.1	±100	~	±1000		±1000	nA
ICC	$V_I = V_{CC} \text{ or } 0,$	IO = 0	5.5 V			4	DNG	80		40	μΑ
∆lcc‡	One input at 0.5 V of Other inputs at 0 or		5.5 V		1.4	2.4	PROL	3		2.9	mA
Ci			4.5 V to 5.5 V		3	10		10		10	pF

[†] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			Vee	T _A =	25°C	SN54H	ICT74	SN74H	ICT74	UNIT
			Vcc	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
		4.5 V	0	27	0	18	0	22	MHz	
fclock	Clock frequency	_	5.5 V	0	30	0	20	0	24	IVITIZ
		4.5 V	16		24	1	20			
.	Pulse duration	PRE or CLR low	5.5 V	14		21	ĬE,	18		ns
tw		CI K high or low	4.5 V	18		27	EL	23		
		CLK high or low	5.5 V	16		24	Q	21		
		Data	4.5 V	12		18	¢.	15		
	Setup time before CLK↑	Dala	5.5 V	11		16		14		
t _{su}	Setup time before CLK		4.5 V	0		80		0		ns
	PRE or CLR inactive	5.5 V	0		0		0		1 !	
+.	Hold time, data after CLK [↑]		4.5 V	0		0		0		-
th	Hold time, data after CLK↑		5.5 V	0		0		0		ns



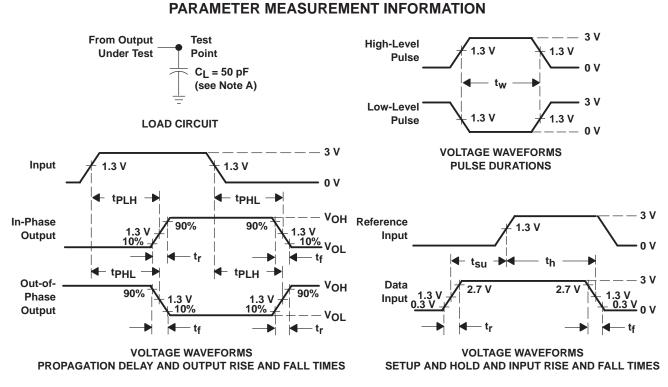
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switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

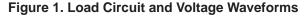
PARAMETER	FROM TO		FROM TO		Vaa	T,	ן ב = 25°C	;	SN54H	CT74	SN74H	ICT74	UNIT
PARAMETER	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT		
,			4.5 V	27	40		18	~	22		MHz		
fmax			5.5 V	30	46		20	IEI,	24				
		4.5 V		21	35		53		44				
. .	PRE or CLR	PRE or CLR Q or Q	5.5 V		17	31	4	48		40	ns		
^t pd	CLK	0	4.5 V		20	28)C.	42		35	115		
	CLK		5.5 V		18	25	Pace Pace	38		31			
		Q or \overline{Q}	4.5 V		8	15	4	22		19	ns		
t			5.5 V		7	14		20		17	115		

operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per flip-flop	No load	35	pF



- NOTES: A. CL includes probe and test-fixture capacitance.
 - B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f = 6 ns.
 - C. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. t_{PLH} and t_{PHL} are the same as t_{pd} .



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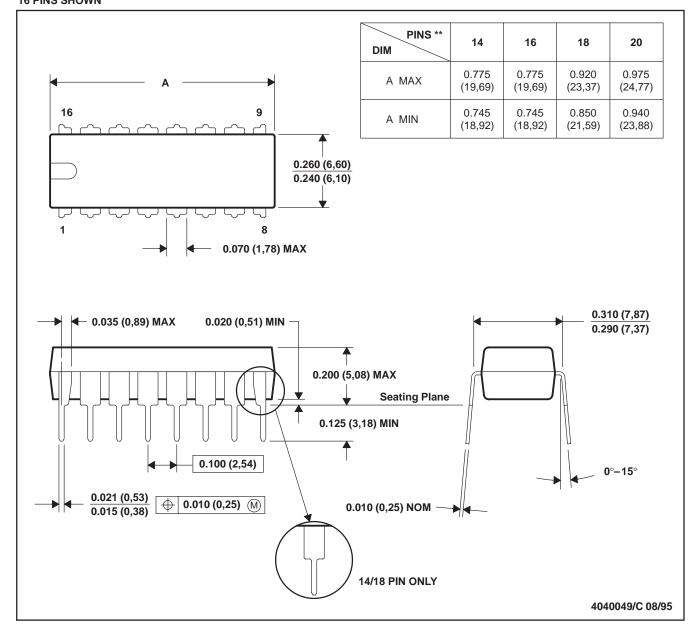
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MECHANICAL DATA

MPDI002A - JANUARY 1995 - REVISED OCTOBER 1995

PLASTIC DUAL-IN-LINE PACKAGE

N (R-PDIP-T**) 16 PINS SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Falls within JEDEC MS-001 (20-pin package is shorter than MS-001).

